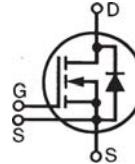


**HiPerFET™ Power
MOSFETs Single Die
MOSFET**

IXFN280N085

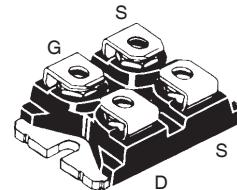
N-Channel Enhancement Mode
Avalanche Rated, High dv/dt, Low t_{rr}



$V_{DSS} = 85V$
 $I_{D25} = 280A$
 $R_{DS(on)} \leq 4.4m\Omega$

miniBLOC, SOT-227 B

E153432



G = Gate D = Drain
S = Source

Either Source terminal at miniBLOC can be used as Main or Kelvin Source

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ C$ to $150^\circ C$	85		V
V_{DGR}	$T_J = 25^\circ C$ to $150^\circ C$, $R_{GS} = 1M\Omega$	85		V
V_{GSS}	Continuous	± 20		V
V_{GSM}	Transient	± 30		V
I_{D25}	$T_C = 25^\circ C$, Chip capability	280	A	
$I_{L(RMS)}$	External Lead Current Limit	200	A	
I_{DM}	$T_C = 25^\circ C$, pulse width limited by T_{JM}	1120	A	
I_A	$T_C = 25^\circ C$	200	A	
E_{AS}	$T_C = 25^\circ C$	4	J	
dV/dt	$I_S \leq I_{DM}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ C$	5		V/ns
P_d	$T_C = 25^\circ C$	700		W
T_J		-55 ... +150		°C
T_{JM}		150		°C
T_{stg}		-55 ... +150		°C
V_{ISOL}	50/60 Hz, RMS $t = 1\text{ min}$ $I_{ISOL} \leq 1\text{ mA}$ $t = 1\text{ s}$	2500 3000	V~ V~	
M_d	Mounting torque Terminal connection torque	1.5/13 1.3/11.5	Nm/lb.in. Nm/lb.in.	
Weight		30		g

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ C$, unless otherwise specified)	Min.	Typ.
BV_{DSS}	$V_{GS} = 0V$, $I_D = 3\text{ mA}$	85		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 8\text{ mA}$	2.0		4.0 V
I_{GSS}	$V_{GS} = \pm 20V$, $V_{DS} = 0V$		± 200	nA
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0V$		100 2	μA mA
$R_{DS(on)}$	$V_{GS} = 10V$, $I_D = 100A$, Note 1		4.4	$m\Omega$

Features

- International standard package
- miniBLOC, with Aluminium nitride isolation
- Low $R_{DS(on)}$ HDMOS™ process
- Rugged polysilicon gate cell structure
- Avalanche rated
- Guaranteed FBSOA
- Low package inductance
- Fast intrinsic Rectifier

Advantages

- Easy to mount
- Space savings
- High power density

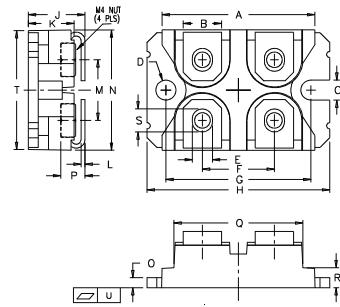
Applications

- DC-DC converters
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- Temperature and lighting controls

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
g_{fs}	$V_{DS} = 10\text{V}$, $I_D = 60\text{A}$, Note 1	60	100	S
C_{iss}			19	nF
C_{oss}			6.4	nF
C_{rss}			3.2	nF
$t_{d(on)}$	Resistive Switching Times $V_{GS} = 10\text{V}$, $V_{DS} = 0.5 \cdot V_{DSS}$, $I_D = 60\text{A}$ $R_G = 1\Omega$ (External)		40	ns
t_r			150	ns
$t_{d(off)}$			112	ns
t_f			60	ns
$Q_{g(on)}$		580		nC
Q_{gs}		77		nC
Q_{gd}		280		nC
R_{thJC}			0.18	°C/W
R_{thCS}		0.05		°C/W

Source-Drain Diode

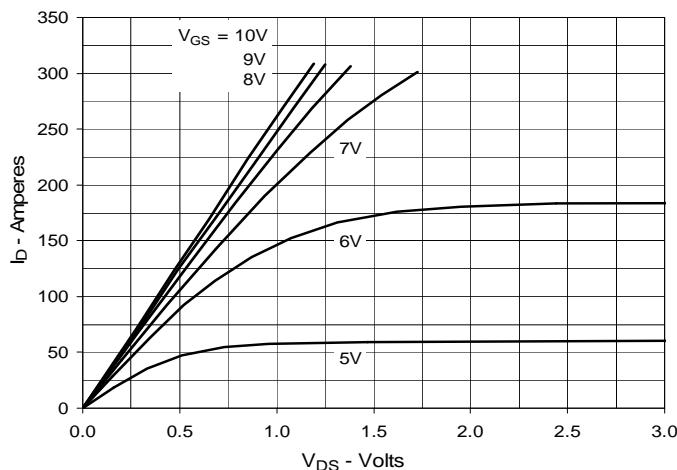
Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
I_s	$V_{GS} = 0\text{V}$		280	A
I_{SM}	Repetitive, pulse width limited by T_{JM}		1120	A
V_{SD}	$I_F = 100\text{A}$, $V_{GS} = 0\text{V}$, Note 1		1.2	V
t_{rr}	$I_F = 50\text{A}$, $-di/dt = 100\text{A}/\mu\text{s}$, $V_R = 50\text{V}$		200	ns
Q_{RM}		0.76		μC
I_{RM}		8.00		A

Note 1: Pulse test, $t \leq 300\mu\text{s}$; duty cycle, $d \leq 2\%$.**miniBLOC, SOT-227 B**

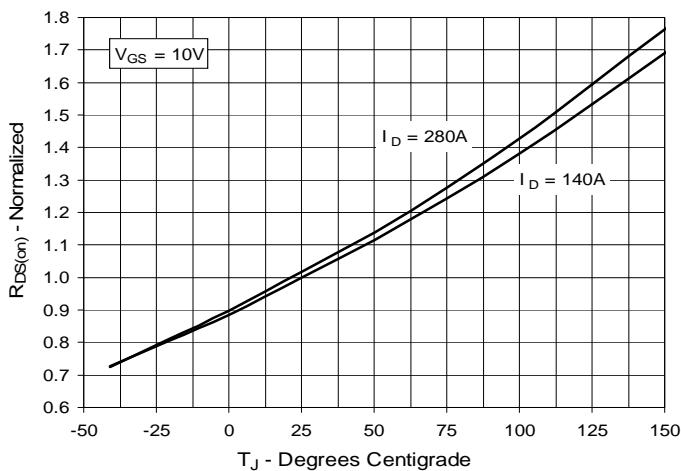
M4 screws (4x) supplied

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	31.50	31.88	1.240	1.255
B	7.80	8.20	0.307	0.323
C	4.09	4.29	0.161	0.169
D	4.09	4.29	0.161	0.169
E	4.09	4.29	0.161	0.169
F	14.91	15.11	0.587	0.595
G	30.12	30.30	1.186	1.193
H	38.00	38.23	1.496	1.505
J	11.68	12.22	0.460	0.481
K	8.92	9.60	0.351	0.378
L	0.76	0.84	0.030	0.033
M	12.60	12.85	0.496	0.506
N	25.15	25.42	0.990	1.001
O	1.98	2.13	0.078	0.084
P	4.95	5.97	0.195	0.235
Q	26.54	26.90	1.045	1.059
R	3.94	4.42	0.155	0.174
S	4.72	4.85	0.186	0.191
T	24.59	25.07	0.968	0.987
U	-0.05	0.1	-0.002	0.004

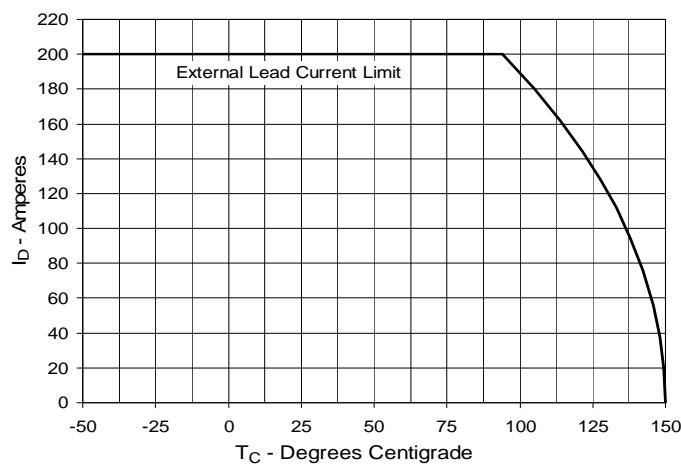
**Fig. 1. Extended Output Characteristics
@ 25°C**



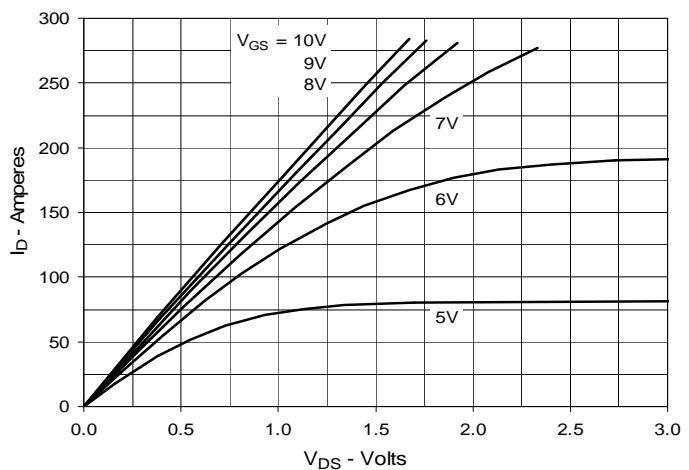
**Fig. 3. $R_{DS(on)}$ Normalized to $I_D = 140A$ Value
vs. Junction Temperature**



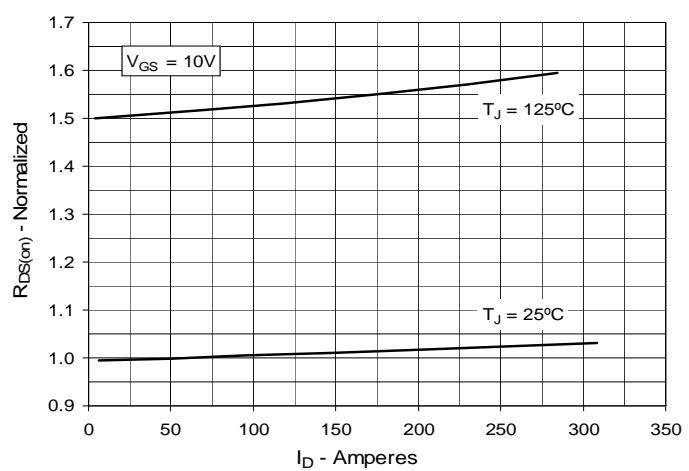
**Fig. 5. Maximum Drain Current vs.
Case Temperature**



**Fig. 2. Output Characteristics
@ 125°C**



**Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 140A$ Value
vs. Drain Current**



**Fig. 6. Forward Voltage Drop of
Intrinsic Diode**

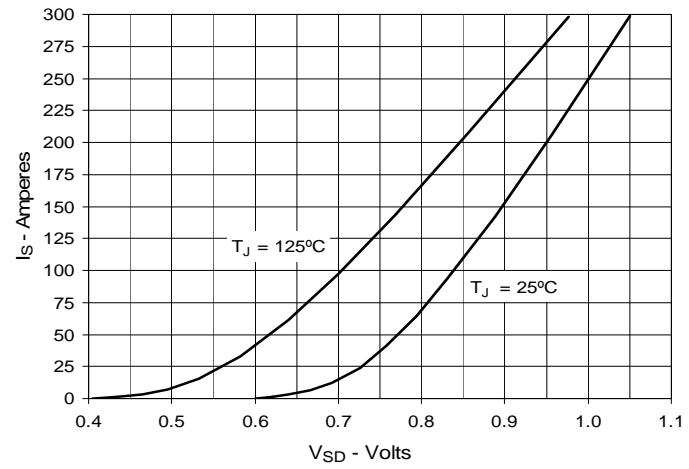
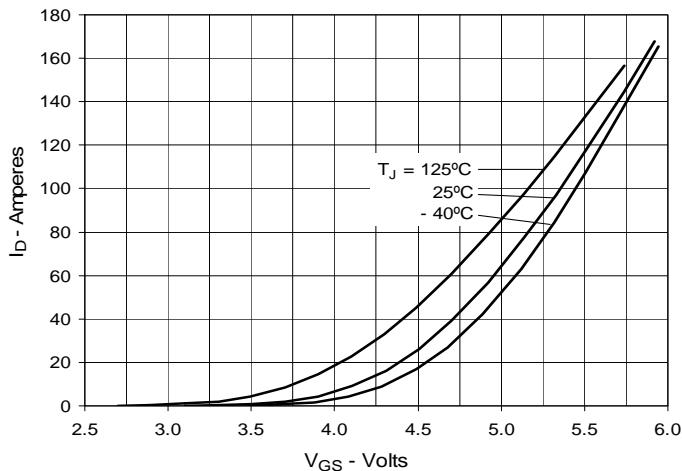
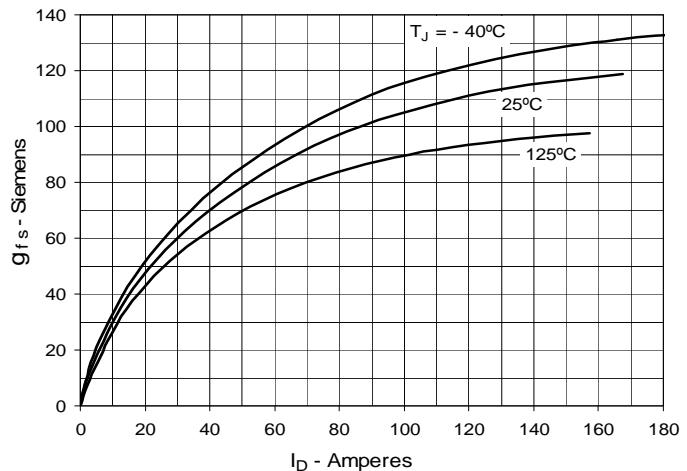
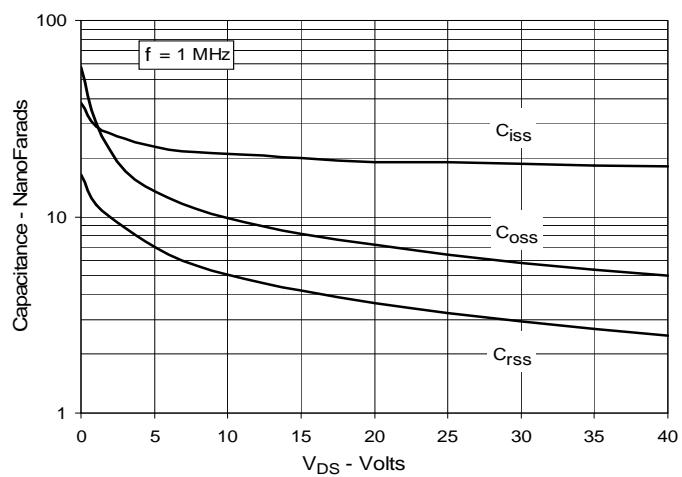
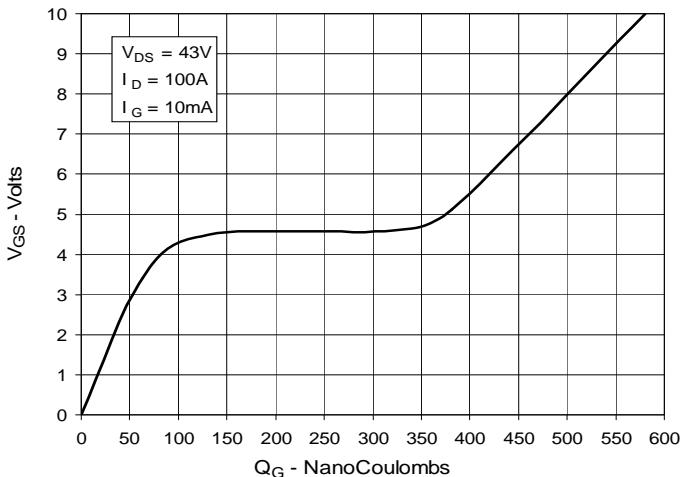
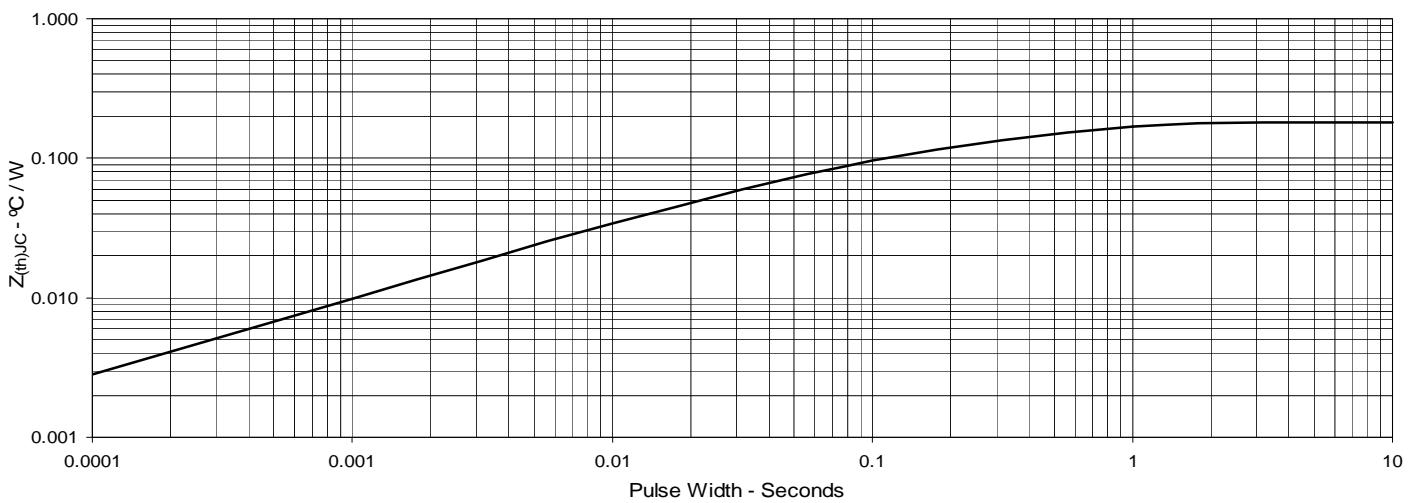
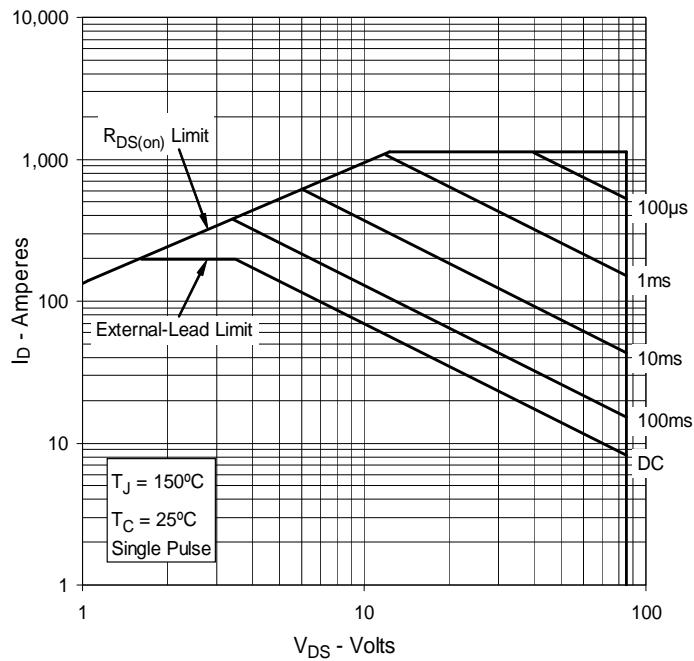


Fig. 7. Input Admittance**Fig. 8. Transconductance****Fig. 9. Capacitance****Fig. 10. Gate Charge****Fig. 11. Maximum Transient Thermal Impedance**

**Fig. 12. Forward-Bias Safe Operating Area
@ $T_C = 25^\circ\text{C}$**



**Fig. 13. Forward-Bias Safe Operating Area
@ $T_C = 75^\circ\text{C}$**

